


<b>Search Notes</b>  	<b>Application/Control No.</b>  10525194	<b>Applicant(s)/Patent Under Reexamination</b>  SAITOH ET AL.
	<b>Examiner</b>  Dawn Garrett	<b>Art Unit</b>  1794

SEARCHED			
Class	Subclass	Date	Examiner
428	690, 917 (see EAST search printouts for all listed class/subclasses)	3/13/07, 1/3/08, 10/7/08	DG
313	504, 506	3/13/07, 1/3/08, 10/7/08	DG
564	426, 427, 429, 433,	3/13/07, 1/3/08, 10/7/08	DG
548	440	3/13/07, 1/3/08, 10/7/08	DG
546	94	3/13/07, 1/3/08, 10/7/08	DG

SEARCH NOTES		
Search Notes	Date	Examiner
see prior search notes page in application file		
updated EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	10/7/08 and 10/19/08	DG
reviewed STIC search of 7/2006	9/22/08	DG
reviewed STIC search of 7/2006	4/7/2009	DG
updated EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	4/7/2009 AND 4/8/2009	DG
reviewed prior EIC 1700 STIC search in application file	11/12/2009	DG
Inventor name search updated	11/12/2009	DG
STN search of registry numbers (see printout)	11/12/2009	DG
updated EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	11/12/2009	DG

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	Interference search done using EAST; UPAD, USPAT, USPGPUB databases searched; keywords searched in claim field (see attached Interference Search history printout)	11/12/2009	DG

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